

Tuesday		8:30 -- 10:00										PLENARY SESSION - Ballroom – Main Level (keynote speaker is Prof. Murat Saatcioglu, from the University of Ottawa, who will talk about "Lessons Learned from the December 26, 2004 Tsunami and Recent Earthquakes, and the Importance of Instrumentation and Measurements in Disaster Mitigation.")									
Room		Laurier – Main Level				Burgundy Room – Mezzanine Level				Renaissance Room – Mezzanine Level				Drawing Room – Main Level				MacDonald Room – Mezzanine Level			
10:30 -- 12:00		Session TA2				Session TB2				Session TC2				Session TD2				Session TE2			
		Analog-to-Digital Converters 1				Advanced Design, Fabrication and Test for System-Level-Integration Technology				Dielectric Properties of Materials				Environmental Monitoring				Medical Measurements and Instrumentation			
		Johan Schoukens Vrije Universiteit Brussel, BELGIUM				Yong-Bin Kim, Northeastern University, USA Nohpill Park, Oklahoma State University, USA				Reza Zoughi University of Missouri-Rolla, USA				Gabriele D'Antona, Politecnico di Milano, Italy				Marco Parvis, Politecnico di Torino, Italy			
		IM5071				IM5325				IM5062				IM5447				IM5191			
		IM5170				IM5367				IM5082				IM5443				IM5135			
		IM5193				IM5533				IM5316				IM5328				IM5206			
		IM5353				IM5226				IM5345				IM5385				IM5271			
		IM5444								IM5393				IM5489				IM5438			
12:00 --1:30		Lunch – Ballroom – Main Level																			
1:30 -- 3:00		Session TA3				Session TB3				Session TC3				Session TD3				Session TE3			
		Analog-to-Digital Converters 2				Built-in-Test and Self-Test				Electromagnetic Measurements 1				Instrumentation and Sensors for Farming				Medical Measurements and Instrumentation			
		Pasquale Daponte University of Sannio, ITALY				Robert Gao, University of Massachusetts Amherst, USA Dennis Hecht, Boeing Company, USA				Alessandro Ferrero Politecnico di Milano, ITALY				Jesus A. Baro, University of Valladolid, Spain Miguel A. Perez, Oviedo University, Spain				Voicu Groza University of Ottawa, CANADA			
		IM5066				IM5117				IM5039				IM5111				IM5389			
		IM5136				IM5118				IM5223				IM5115				IM5460			
		IM5171				IM5119				IM5083				IM5473				IM5561			
		IM5452				IM5480				IM5218				IM5477				IM5565			
3:30 -- 5:00		Session TA4				Session TB4				Session TC4				Session TD4				Session TE4			
		Analog-to-Digital Converters 3				System-On-Chip (SOC) Integrated Circuits – Design and Test				Electromagnetic Measurements 2				RF and Microwave Moisture Sensing Applications				Medical Measurements and Instrumentation			
		Vladimir Haasz Czech Technical University, CZECH REPUBLIC				Sunil Das University of Ottawa, CANADA				Dan Neculescu University of Ottawa, CANADA				Samir Trabelsi, US Department of Agriculture, USA Stuart Nelson, US Department of Agriculture, USA				Boguslaw J. Jarosz Carleton University CANADA			
		IM5158				IM5552				IM5036				IM5057				IM5340			
		IM5244				IM5383				IM5175				IM5131				IM5358			
		IM5332				IM5451				IM5183				IM5255				IM5485			
		IM5507				IM5546				IM5213				IM5475				IM5337			
5:00 -- 7:00		IM5528				IM5525				IM5220				IM5434				IM5569			
		Poster Session T5 (Adam Room – Main Level)																			
		T5.1 Data Acquisition and Measurements Colin Clark Brunel University, UK						T5.2 Sensors Henrik Lundin Royal Institute of Technology, SWEDEN						T5.3 Signal Processing Sergio Rapuano University of Sannio, ITALY							
		IM5159		IM5208		IM5408		IM5268		IM5412		IM5242		IM5065		IM5146		IM5295		IM5429	
		IM5272		IM5234		IM5334		IM5279		IM5446		IM5286		IM5239		IM5155		IM5305		IM5435	
		IM5323		IM5456		IM5351		IM5330		IM5469		IM5401		IM5241		IM5160		IM5317		IM5436	
		IM5362		IM5549		IM5267		IM5360		IM5490		IM5508		IM5025		IM5214		IM5333		IM5442	
IM5538		IM5144		IM5248		IM5372		IM5044		IM5032		IM5043		IM5247		IM5335					
IM5024		IM5311		IM5527		IM5037		IM5045		IM5230		IM5073		IM5250		IM5369					
IM5035		IM5466				IM5182		IM5092				IM5104		IM5276		IM5370					
IM5176		IM5559				IM5265		IM5143				IM5140		IM5294		IM5371					

Wednesday																					
Room	L'Orangerie – Mezzanine			Burgundy Room – Mezzanine Level			Renaissance Room – Mezzanine Level			Canadian – Lower Level		MacDonald Room – Mezzanine Level									
8:30 -- 10:00	Session WA1			Session WB1			Session WC1			Session WD1		Session WE1									
	Sigma-Delta Modulators			VLSI			Power measurements			Position measurements		Biologically Inspired Instrumentation, Sensors, and Perception Techniques									
	Izzet Kale University of Westminster Great Britain			Serge Demidenko Monash University Malaysia			Vedran Bilas University of Zagreb CROATIA			Pierre Payeur University of Ottawa CANADA		Abdulmotaieb El Saddik University of Ottawa CANADA									
	IM5114			IM5306			5459			IM5099		IM5020									
	IM5479			IM5331			IM5095			IM5228		IM5225									
	IM5501			IM5384			IM5185			IM5431		IM5516									
	IM5519			IM5413			IM5448			IM5464		IM5556									
10:30 -- 12:00	Session WA2			Session WB2			Session WC2			Session WD2		Session WE2									
	System Identification			Spectroscopy			Power measurements			Measurements for industrial applications		Low Frequency Measurements									
	Tyseer Aboulnasr University of Ottawa, CANADA			Pasquale Arpaia Universita' del Sannio ITALY			Matteo Bertocco University of Padova, ITALY			Kim R. Fowler Johns Hopkins University-APL, USA		Peter S. Filipski National Research Council, CANADA									
	IM5000			IM5152			IM5001			IM5048		IM5010									
	IM5004			IM5256			IM5536			IM5313		IM5275									
	IM5007			IM5399			IM5157			IM5314		IM5312									
	IM5058			IM5524			IM5278			IM5361		IM5492									
12:00 -- 1:30	IM5531			IM5524			IM5288			IM5478		IM5499									
	Lunch – Ballroom – Main Level																				
1:30 -- 3:00	Session WA3			Session WB3			Session WC3			Session WD3		Session WE3									
	Signal Processing 1			Optical transducers			Power Quality			Measurements for industrial applications		Imaging Systems and Techniques									
	Tadeusz P. Dobrowiecki Budapest University of Technology and Economics, HUNGARY			Branislav Djokic National Research Council of Canada, CANADA			Domenico Alessandro Lampasi University of Rome "La Sapienza", ITALY			Peter Wide Örebro University SWEDEN		George C. Giakos, University of Akron, USA Matteo Pastorino University of Genoa, Italy									
	IM5029			IM5168			IM5199			IM5236		IM5069									
	IM5194			IM5373			IM5320			IM5344		IM5133									
	IM5310			IM5409			IM5347			IM5363		IM5269									
	IM5343			IM5521			IM5487			IM5329		IM5386									
3:30 -- 5:00	Session WA4			Session WB4			Session WC4			Session WD4		Session WE4									
	Signal Processing 2			Optical sensors			System Health Measurement			Virtual Labs for Education in Instrumentation and Measurement		Perception and Modelling of Three-Dimensional Objects and Scenes									
	Rafik Goubran Carleton University CANADA			Wojtek J. Bock University of Quebec at Outaouais CANADA			Kang Lee NIST USA			Theodore Laopoulos, Aristotle University, Greece Domenico Grimaldi, Università della Calabria, Italy		Eric Dubois University of Ottawa CANADA									
	IM5072			IM5177			IM5179			IM5283		IM5127									
	IM5178			IM5188			IM5181			IM5149		IM5366									
	IM5243			IM5299			IM5237			IM5470		IM5400									
	IM5395			IM5512			IM5364			IM5515		IM5418									
5:00 -- 7:00	IM5396			IM5520			IM5365			IM5535											
	Poster Session W5 and Reception (Adam Room – Main Level)																				
	W5.1 Industrial Applications I Bilas Vedran University of Zagreb, CROATIA				W5.2 Medical Applications Andy ADLER University of Ottawa, CANADA				W5.3 Industrial Applications II Rami Abielmona University of Ottawa, CANADA												
	IM5187		IM5382		IM5472		IM5338		IM5054		IM5289		IM5124		IM5212		IM5455		IM5202		
	IM5134		IM5424		IM5189		IM5453		IM5055		IM5548		IM5293		IM5354		IM5468		IM5540		
	IM5150		IM5488		IM5249		IM5486		IM5074		IM5216		IM5113		IM5537		IM5482				
	IM5192		IM5493		IM5273		IM5005		IM5076				IM5154		IM5254		IM5498				
	IM5224		IM5108		IM5315		IM5011		IM5091				IM5017		IM5016		IM5050				
	IM5296		IM5109		IM5227		IM5021		IM5126				IM5098		IM5015		IM5260				
	IM5324		IM5110		IM5357		IM5034		IM5209				IM5163		IM5026		IM5292				
	IM5359		IM5304		IM5568		IM5052		IM5252				IM5174		IM5300		IM5450				
	7:00 PM	Banquet – Ballroom – Main Level																			

Thursday													
Room	L'Orangerie – Mezzanine			Burgundy Room – Mezzanine Level			Renaissance Room – Mezzanine Level			Drawing Room – Main Level		MacDonald Room – Mezzanine Level	
8:30 -- 10:00	Session YA1			Session YB1			Session YC1			Session YD1		Session YE1	
	Signal Processing 3			Sensor Arrays			Temperature measurement			Measurement in Ground Transportation Systems		Virtual Environments	
	Jerome J. Blair Bechtel Nevada, USA			Wieslaw Winiiecki Warsaw University of Technology POLAND			Henry Schriemer University of Ottawa, CANADA			Georg Brasseur, Graz University of Technology, Austria Frans C.A. Groen, Science University of Amsterdam, The Netherlands		Shervin Shirmohammadi University of Ottawa CANADA	
	IM5003			IM5023			IM5096			IM5093		IM5403	
	IM5502			IM5139			IM5197			IM5122		IM5471	
	IM5307			IM5219			IM5203			IM5258		IM5562	
	IM5504			IM5428			IM5229			IM5355		IM5566	
	IM5376			IM5341						IM5534			
10:30 -- 12:00	Session YA2			Session YB2			Session YC2			Session YD2		Session YE2	
	Signal Processing 4			Sensors			Mechanical quantities			Computer Networks Measurements 1		Medical Applications	
	Piet M.T. Broersen Delft University of Technology THE NETHERLANDS			Paolo Carbone University of Perugia, ITALY			Victor Aitken Carleton University, CANADA			Axel Sikora University of Cooperative Education Loerrach, GERMANY		Mart Min Tallinn Technical University, ESTONIA	
	IM5075			IM5522			IM5064			IM5449		IM5046	
	IM5147			IM5106			IM5169			IM5245		IM5270	
	IM5173			IM5132			IM5319			IM5474		IM5416	
	IM5342			IM5263			IM5148			IM5476		IM5432	
				IM5303						IM5497			
12:00 -- 2:00	Poster Session Y5 and Lunch (Adam Room – Main Level)												
	Y5.1 Computer Networks and Microelectronics Ana Maria Cretu University of Ottawa, CANADA					Y5.2 Imaging Techniques and Software Applications Fabrizio Russo University of Trieste, ITALY							
	IM5541	IM5161	IM5167	IM5458		IM5378	IM5105	IM5084					
	IM5463	IM5172		IM5422		IM5349	IM5128	IM5019					
	IM5059	IM5070	IM5287	IM5427		IM5077	IM5129	IM5380					
	IM5184	IM5207	IM5308	IM5204		IM5078	IM5141	IM5381					
	IM5368	IM5336	IM5318	IM5322		IM5079	IM5165	IM5426					
	IM5523	IM5339	IM5321	IM5517		IM5080	IM5200	IM5518					
	IM5437	IM5483	IM5346	IM5505		IM5081	IM5217	IM5404					
	IM5008		IM5441	IM5491		IM5094	IM5257	IM5274					
		IM5500											
2:00 -- 3:30	Session YA3			Session YB3			Session YC3			Session YD3		Session YE3	
	Uncertainty			Sensor Networks			Soft Computing 1			Sensor Technologies for Intelligent Robotics		Real-time Measurements	
	Roman Morawski Measurement Microsystems Inc. CANADA			Andrzej Barwicz Measurement Microsystems Inc., CANADA			Pierre Payeur University of Ottawa, CANADA Ana Maria Cretu University of Ottawa, CANADA			Gourab Sen Gupta, Massey University, New Zealand & Singapore Polytechnic, Singapore Chris Messom, Massey University, New Zealand		Jiyong Zhao University of Ottawa CANADA	
	IM5205			IM5088			IM5102			IM5028		IM5246	
	IM5419			IM5195			IM5266			IM5121		IM5097	
	IM5465			IM5262			IM5402			IM5557		IM5145	
				IM5484			IM5461			IM5558		IM5510	
							IM5326			IM5563			
4:00 -- 5:30	Session YA4			Session YB4			Session YC4			Session YD4		Session YE4	
	Optical instrumentation and measurement			Multi-Sensor and Model-Based Sensor Systems			Soft Computing 2			Computer Networks Measurements 2		FSM Testing and Instrumentation	
	Jianping YAO University of Ottawa, CANADA			O. Kanoun, H.-R. Tränkle, University of the Bundeswehr Munich, Germany			Fabrizio Russo University of Trieste, ITALY			Barna Szabados McMaster University, CANADA		Hasan Ural University of Ottawa, CANADA	
	IM5018			IM5544			IM5280			IM5038		IM5379	
	IM5142			IM5374			IM5291			IM5445		IM5397	
	IM5190			IM5494			IM5410			IM5211		IM5532	
	IM5297			IM5543			IM5251			IM5545			
	IM5457			IM5529			IM5506			IM5298			